

Defect-oriented test generation and fault simulation in the environment of MOSCITO

Schneider, Andre; Diener, Karl-Heinz; Gramatova, Elena; Fisherova, Maria; **Ivask, Eero; Ubar, Raimund-Johannes**; Pleskacz, Witold A.; Kuzmicz, W. BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 303-306 : ill

High-level synthesis and test in the MOSCITO-based virtual laboratory

Schneider, Andre; Diener, Karl-Heinz; **Jervan, Gert**; Peng, Z.; **Raik, Jaan; Ubar, Raimund-Johannes**; Hollstein, Thomas; Glesner, M. BEC 2002 : proceedings of the 8th Biennial Baltic Electronics Conference : October 6-9, 2002, Tallinn, Estonia 2002 / p. 287-290 : ill

Integrated design and test generation under Internet based environment MOSCITO

Schneider, Andre; **Ivask, Eero; Ubar, Raimund-Johannes** Euromicro Symposium on Digital System Design : Architectures, Methods and Tools : September 4-6, 2002, Dortmund, Germany : proceedings 2002 / p. 187-194 : ill
<http://dx.doi.org/10.1109/DSD.2002.1115368>

Integration of digital test tools to the internet-based environment MOSCITO

Schneider, Andre; Diener, Karl-Heinz; Elst, Günter; **Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes** SCI 2003 : the 7th World Multiconference on Systemics, Cybernetics and Informatics : July 27-30, 2003, Orlando, Florida, USA : proceedings. Volume VIII, Applications of Informatics and Cybernetics in Science and Engineering 2003 / p. 136-141 : ill

Internet based test generation and fault simulation

Ivask, Eero; Ubar, Raimund-Johannes; Raik, Jaan; Schneider, Andre IEEE Design and Diagnostics of Electronic Circuits and Systems - IEEE DDECS 2001 : Fourth International Workshop on IEEE Design and Diagnostics of Electronic Circuits and Systems : Györ, Hungary, April 18-20, 2001 2001 / p. 57-60 : ill

Internet-based collaborative test generation with MOSCITO [Electronic resource]

Schneider, Andre; **Ivask, Eero**; Miklos, P.; **Raik, Jaan**; Diener, Karl-Heinz; **Ubar, Raimund-Johannes**; Cibakova, Tatiana; Gramatova, Elena SIGDA publications on CD-ROM : DATE'02 : Design, Automation and Test in Europe, Paris, France, March 4-8, 2002 2002 / [6] p. [CD-ROM]

Internet-based testability-driven test generation in the virtual environment MOSCITO

Schneider, Andre; Diener, Karl-Heinz; Elst, G.; **Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes** International Federation for Information Processing IFIP : International Workshop on IP-Based SoC Design 2002 : proceedings : Grenoble, October 30-31, 2002 2002 / p. 357-362 : ill <http://publica.fraunhofer.de/dokumente/N-287433.html>

Internet-basierter Systementwurf mit MOSCITO

Schneider, Andre; Schneider, Peter; Gramatova, Elena; **Ivask, Eero** Entwurf Integrierter Schaltungen : 10. E.I.S.-Workshop : Präsentationen der ITG-Fachtagung : vom 3. bis 5. April 2001 in Dresden 2001 / S. 295-296 : ill

Web-based environment for digital electronics test tools

Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes; Schneider, Andre Virtual Enterprises and collaborative networks : IFIP 18th World Computer Congress [and] TC5/WG5.5 - 5th Working Conference on Virtual Enterprises : 22-27 August 2004, Toulouse, France 2004 / p. 435-442 : ill

VILAB test generation tools running under the MOSCITO system

Schneider, Andre; **Ivask, Eero; Raik, Jaan; Ubar, Raimund-Johannes** VILAB User Forum : Györ, Hungary, 2001 2001 / [12] p